

<b>Notice of References Cited</b>	Application/Control No. 10/567,317		Applicant(s)/Patent Under Reexamination JONES ET AL.	
	Examiner HAI V. NGUYEN		Art Unit 2618	Page 1 of 6

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,278,871 A	01-1994	Rasky et al.	375/343
*	B	US-5,343,496 A	08-1994	Honig et al.	370/342
*	C	US-6,078,796 A	06-2000	Ling, Fuyun	455/234.1
*	D	US-6,167,039 A	12-2000	Karlsson et al.	370/342
*	E	US-6,377,607 B1	04-2002	Ling et al.	375/130
*	F	US-6,370,397 B1	04-2002	Popovic et al.	455/561
*	G	US-6,408,023 B1	06-2002	Abdesselem et al.	375/232
*	H	US-2002/0097785 A1	07-2002	Ling et al.	375/147
*	I	US-2002/0136188 A1	09-2002	Kim, Younglok	370/342
*	J	US-2003/0026325 A1	02-2003	De et al.	375/147
*	K	US-2003/0026236 A1	02-2003	De et al.	370/342
*	L	US-2003/0043767 A1	03-2003	Pan et al.	370/335
*	M	US-6,542,562 B1	04-2003	Ostberg et al.	375/350

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/567,317		Applicant(s)/Patent Under Reexamination JONES ET AL.	
	Examiner HAI V. NGUYEN		Art Unit 2618	Page 2 of 6

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0081658 A1	05-2003	Messier et al.	375/147
*	B	US-2003/0210667 A1	11-2003	Zhengdi, Qin	370/335
*	C	US-2004/0033791 A1	02-2004	Schmidl et al.	455/137
*	D	US-2004/0032917 A1	02-2004	Hwang et al.	375/343
*	E	US-6,707,864 B2	03-2004	Kim, Younglok	375/343
*	F	US-2004/0120300 A1	06-2004	Saquib, Mohammad	370/342
*	G	US-2004/0146095 A1	07-2004	Umeno et al.	375/150
*	H	US-6,816,470 B2	11-2004	Kim et al.	370/280
*	I	US-2004/0264591 A1	12-2004	Malm et al.	375/261
*	J	US-2004/0264604 A1	12-2004	Malette et al.	375/340
*	K	US-2005/0013350 A1	01-2005	Coralli et al.	375/148
*	L	US-6,882,619 B1	04-2005	Gerakoulis, Diakoumis	370/209
*	M	US-2005/0084043 A1	04-2005	Yang et al.	375/346

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/567,317		Applicant(s)/Patent Under Reexamination JONES ET AL.	
	Examiner HAI V. NGUYEN		Art Unit 2618	Page 3 of 6

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0094740 A1	05-2005	Borran et al.	375/267
*	B	US-6,891,897 B1	05-2005	Bevan et al.	375/265
*	C	US-2005/0102600 A1	05-2005	Anandakumar, Anand	714/755
*	D	US-2005/0141466 A1	06-2005	Krupka, Eyal	370/338
*	E	US-6,956,888 B2	10-2005	Zhengdi, Qin	375/130
*	F	US-6,956,888	10-2005	Zhengdi, Qin	375/130
*	G	US-2005/0265291 A1	12-2005	Bar-Ness et al.	370/335
*	H	US-6,980,602 B1	12-2005	Kleinerman et al.	375/262
*	I	US-6,975,669 B2	12-2005	Ling et al.	375/141
*	J	US-2005/0286406 A1	12-2005	Jeon et al.	370/208
*	K	US-2006/0007895 A1	01-2006	Coralli et al.	370/335
*	L	US-2006/0023636 A1	02-2006	Farhang-Boroujeny et al.	370/252
*	M	US-6,996,160 B2	02-2006	Li et al.	375/148

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/567,317		Applicant(s)/Patent Under Reexamination JONES ET AL.	
	Examiner HAI V. NGUYEN		Art Unit 2618	Page 4 of 6

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,999,634	02-2006	Hong, Sung Hoon	382/275
*	B	US-6,996,385 B2	02-2006	Messier et al.	455/226.3
*	C	US-7,042,929 B2	05-2006	Pan et al.	375/148
*	D	US-7,054,300 B2	05-2006	Pan et al.	370/342
*	E	US-2006/0126761 A1	06-2006	Bernhardsson et al.	375/340
*	F	US-2006/0146763 A1	07-2006	Supplee et al.	370/335
*	G	US-2006/0171418 A1	08-2006	Casini et al.	370/474
*	H	US-2006/0233223 A1	10-2006	Pan et al.	375/147
*	I	US-2007/0040704 A1	02-2007	Smee et al.	340/981
*	J	US-7,184,497 B2	02-2007	Jeske et al.	375/346
*	K	US-2007/0041428 A1	02-2007	Wang et al.	375/146
*	L	US-2007/0076643 A1	04-2007	Yang et al.	370/310
*	M	US-2007/0291641 A1	12-2007	Pan et al.	370/210

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/567,317		Applicant(s)/Patent Under Reexamination JONES ET AL.	
	Examiner HAI V. NGUYEN		Art Unit 2618	Page 5 of 6

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2007/0286292 A1	12-2007	Moelker et al.	375/241
*	B	US-7,313,172 B2	12-2007	Pan et al.	375/148
*	C	US-7,349,463 B1	03-2008	Pajukoski et al.	375/148
*	D	US-7,349,667 B2	03-2008	Magee et al.	455/63.4
*	E	US-7,349,379 B2	03-2008	Schmidl et al.	370/342
*	F	US-2008/0062860 A1	03-2008	Kwak et al.	370/210
*	G	US-2008/0095216 A1	04-2008	Pan et al.	375/148
*	H	US-7,376,176 B2	05-2008	Zhao et al.	375/148
*	I	US-7,386,030 B2	06-2008	Asghar et al.	375/142
*	J	US-7,386,033 B2	06-2008	Pan et al.	375/147
*	K	US-7,386,057 B2	06-2008	Ito et al.	375/267
*	L	US-7,408,978 B2	08-2008	Pan et al.	375/150
*	M	US-7,411,997 B2	08-2008	Umeno et al.	375/150

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/567,317		Applicant(s)/Patent Under Reexamination JONES ET AL.	
	Examiner HAI V. NGUYEN		Art Unit 2618	Page 6 of 6

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,440,524 B2	10-2008	Hwang et al.	375/343
*	B	US-7,457,379 B2	11-2008	Yang et al.	375/346
*	C	US-7,447,255 B2	11-2008	De et al.	375/147
*	D	US-7,453,933 B2	11-2008	Jeske et al.	375/227
*	E	US-7,460,580 B2	12-2008	Pan et al.	375/141
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.